Abstracts

Contactless Electrical Characterization of MMICs by Device Internal Electrical Sampling Scanning-Force-Microscopy

C. Bohm, C. Roths and E. Kubalek. "Contactless Electrical Characterization of MMICs by Device Internal Electrical Sampling Scanning-Force-Microscopy." 1994 MTT-S International Microwave Symposium Digest 94.3 (1994 Vol. III [MWSYM]): 1605-1608.

For the first time a scanning force microscope based test system is used for device internal electrical characterization of monolithic microwave integrated circuits (MMIC) based on lll-V-semiconductor material up to 40 GHz. Measurements on a coplanar waveguide and within a traveling wave amplifier (TWA) demonstrate the capability for a device internal function- and failure analysis of MMICS. The experimental results are completed by network analyzer measurements.

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